

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/670,114	<b>Applicant(s)/Patent under Reexamination</b> MOCHIDA ET AL.
<b>Examiner</b> Dave Czekaj	<b>Art Unit</b> 2621	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner